To: T10 Technical Committee
From: Mark Overby, NVIDIA Corporation (moverby@nvidia.com)
Date: 9 November 2005
Subject: T10/05-360r2 SPC-4: Extended self test completion time value update

Revision History

Revision 0 - Initial draft of document
Revision 1 - Updated title and date
       From Rob Elliot comments: Clarified new text with "extended self-test" instead of "self-test". Removed "will".
Revision 2 - Updated FFFFh seconds to 65535 seconds per request from 9 November CAP meeting

Related Documents

SPC-4 (T10/1731-D) Revision 1a

1 Overview

This proposal adds language to the definition of the extended self test completion time field, from the control mode page, to indicate how to interpret a value of FFFFh in that field.

2 Document Changes

2.1 Changes to SPC-4 (T10/1731-D r1a)

Modify the paragraph from SPC-4, in subclause 7.4.6, describing the extended self test completion time field to read as follows.

The EXTENDED SELF-TEST COMPLETION TIME field contains advisory data that is the time in seconds that the device server requires to complete an extended self-test when the device server is not interrupted by subsequent commands and no errors occur during processing of the self-test. The application client should expect this time to increase significantly if other commands are sent to the logical unit while a self-test is in progress or if errors occur during the processing of the self-test. Device servers supporting SELF-TEST CODE field values other than 000b for the SEND DIAGNOSTIC command (see 6.28) shall support the EXTENDED SELF-TEST COMPLETION TIME field. The EXTENDED SELF-TEST COMPLETION TIME field is not changeable. A value of FFFFh indicates that the extended self-test takes **65535** seconds or longer.